

# Supplementary Materials

## Toward Enhanced Humidity Stability of Triboelectric Mechanical Sensors via Atomic Layer Deposition

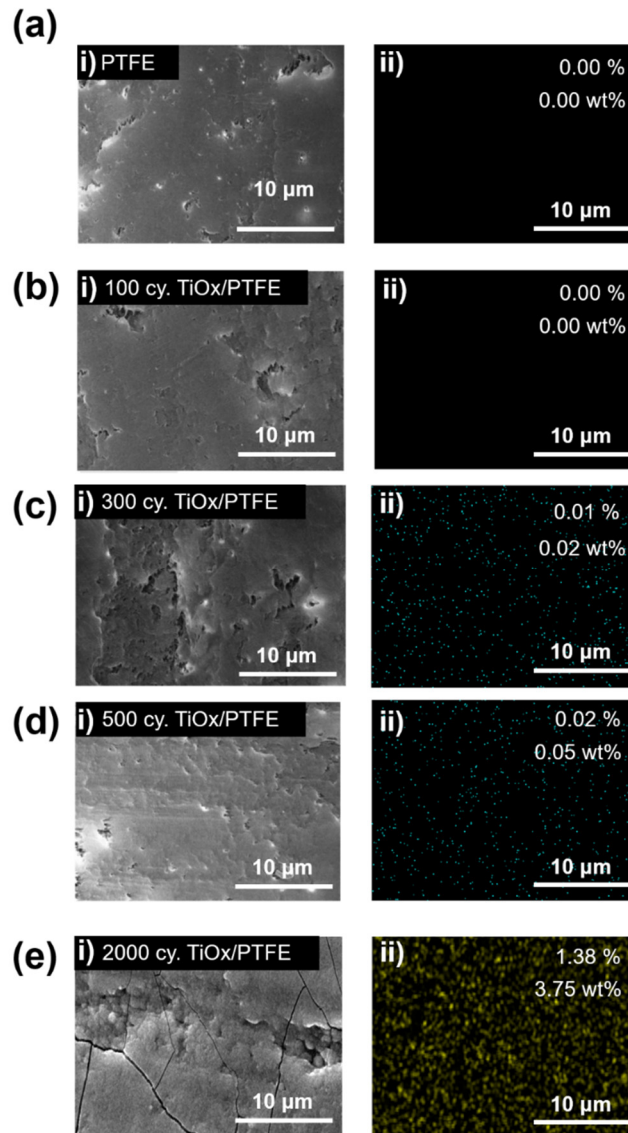
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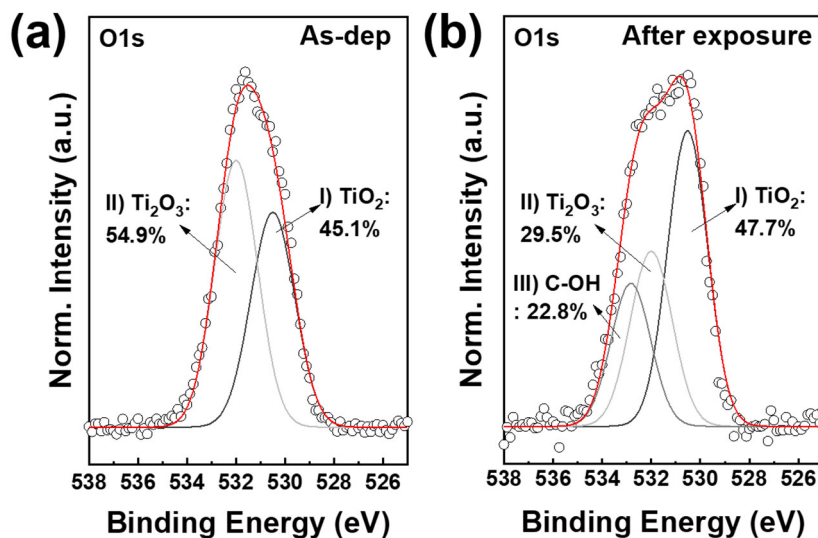
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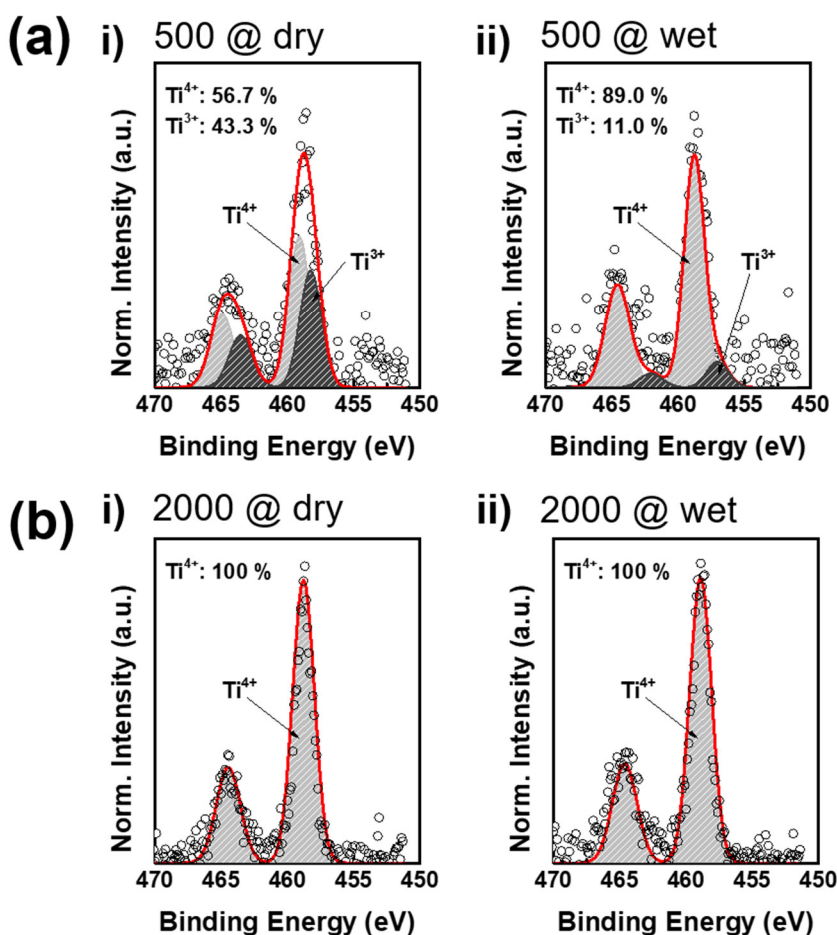
† These authors equally contributed to this work.



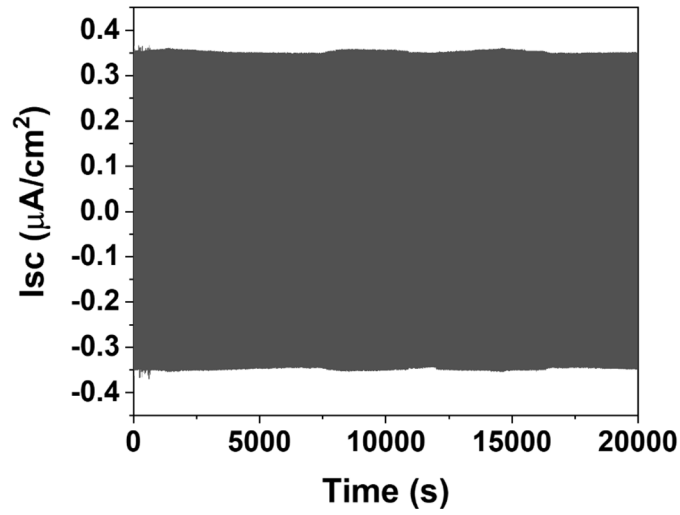
**Figure S1.** FE-SEM and EDS elemental mapping of Ti on (a) pristine PTFE film and ALD-TiO<sub>x</sub>/PTFE films grown with (b) 100, (c) 300, (d) 500, and (e) 2000 ALD cycles. i) FE-SEM image in top view and ii) EDS elemental mapping of Ti on ALD-TiO<sub>x</sub>/PTFE films.



**Figure S2.** Deconvoluted XPS O 1s spectra of 300-TiO<sub>x</sub>/PTFE at (a) dry (RH 10%) and (b) humid conditions (RH 99%).

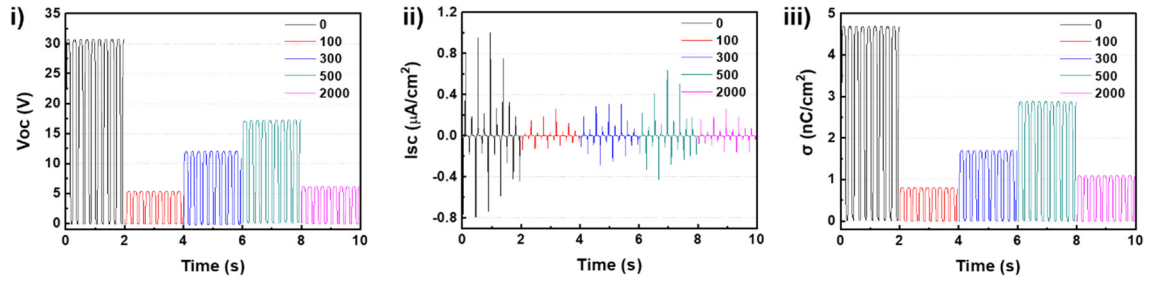


**Figure S3.** Deconvoluted XPS Ti 2p spectra of (a) 500-TiO<sub>x</sub>/PTFE and (b) 2000-TiO<sub>x</sub>/PTFE films. Ti 2p spectrum of the i) as-deposited specimen and ii) after moisture exposure.

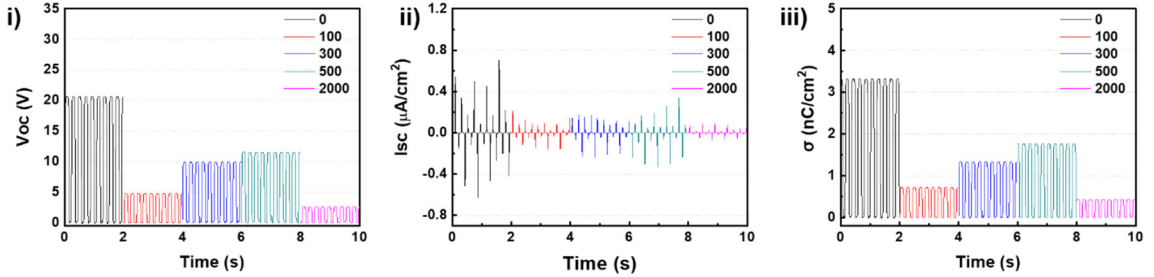


**Figure S4.** Mechanical durability test of 300-TiO<sub>x</sub>/PTFE film under the cyclic mechanical stimulation for 20,000 s. To evaluate the mechanical stability, the contact load of 5 N and contact frequency of 3 Hz were applied.

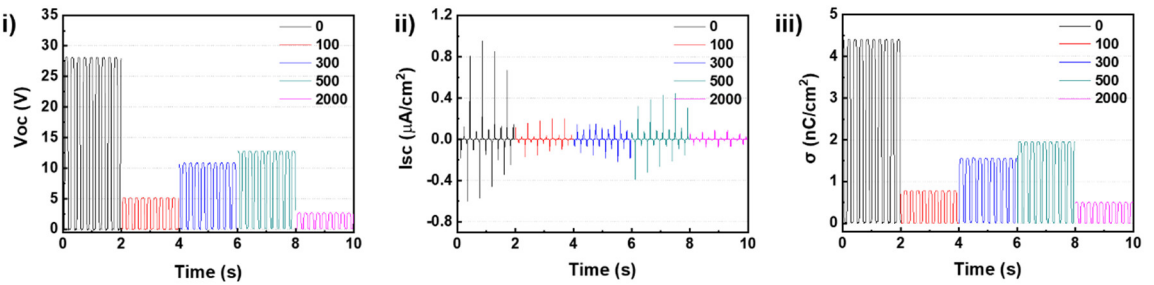
**(a) Triboelectric performance in dry environment (RH 10 %)**



**(b) In highly humid condition (RH 99 %, 24 h)**



**(c) After natural drying process at room temperature**



**Figure S5.** Measured triboelectric outputs of ALD-TiO<sub>x</sub>/PTFE films in (a) dry (RH 10%) and (b) humid environments (RH 99%). (c) Triboelectric signals after a natural drying process: i) open circuit voltage, ii) short circuit current, and iii) charge density.